## SiM: STM iMproved

## $nano\mathbf{REV}^{\mathsf{TM}}$ Specification Sheet Version 4.2.0



Quazar Technologies Pvt. Ltd. New Delhi, India

## Specifications of $nano\mathbf{REV}^\mathsf{TM}$ : Air STM

Electronica		
Electronics  Main Down Cumply input	220 240V AC/50 Hz 0 0W	
Main Power Supply input	220-240V AC/50 Hz, 9.0W	
Power Supply outputs	$+5V DC, \pm 15V DC, 110V DC, 110V AC$	
Computer Interface	Parallel Port	
Measurement Channels	Single channel 16-bit A/D converter	
Scan generator	4-channel 12-bit D/A converter	
Scan speed	51ms/line (max) for 256 data-points	
	in each line (Dual imaging mode)	
Scan drive signals	$\pm 110 \text{V DC}$	
Slope compensation	Both Hardware and Software horizontal	
	& vertical Slope Compensation	
Tunnel Current Set Point Adj.	-5nA to $+5$ nA in steps of $0.1$ nA (Option 1)	
	-25nA to $+25$ nA in steps of 0.5nA (Option 2)	
	(Any one of the option is provided as per user	
	requirement)	
Servo Control	Analog Feedback Parameter (Gain, Time	
	Constant, T.C. Setpoint) Adjustments	
Walker Display	LCD Display of piezo-electric	
	walker's direction and no. of steps	
Bias Settings	-10,000mV to $+10,000$ mV in Steps of 5mV	
I-V Spectroscopy	5mV bias resolution for 1024 data points,	
	I/V, $dI/dV$ & Normalized $dI/dV$ plots,	
	Export to ASCII option available	
I-V Spectroscopy Modes	- Point mode	
	- Line mode	
	- Grid mode	
I-Z Spectroscopy	Tunneling Current vs Distance plots,	
	Conductance vs Distance plots	
	(Normal & Semilog), Export to ASCII	
	option available	

STM Measurement Sizes	Min.	Max.	X/Y
	Area	Area	Resolution (min.)
XL Area	$34.6 \times 34.6 nm^2$	$2.6 \times 2.6 \mu m^2$	0.675nm
Large Area	$17.3 \times 17.3 nm^2$	$260 \times 260 nm^2$	67.5pm
Small Area	$34.5 \times 34.5 \text{Å}^2$	$51.8 \times 51.8 nm^2$	13.5pm
Z-resolution	Analog Mode: $0.008 - 0.01nm$		
	Digital : 0.025 -	-0.05nm (Using 1	2-bit DAC)
Scan orientation	Horizontal and Vertical		
Max Z Range	$\pm 350$ to $\pm 500nm$ (Full-Stretch and Full-Retract)		
Imaging modes	Constant Current, Constant Height and		
	Dynamical Conductance Imaging		

Software	
Image Display	Dual Imaging Window for Scan and Retrace
	Image Display
CRO	In-built software CRO plotting imaging signal
	during scans
Sample Navigator	Graphical assistant for localized zooming
	w.r.t. a large area scan
3D	Colored 3D renderings, selection of color
	look-up tables
Data Export	Export to standard image file formats like
-	jpg, png, ASCII, postscript format.
Analysis Functions	Line (Single line profile) Extraction,
·	localized Zooming, Roughness Display,
	Measure length & angles on the images,
	2D Fast Fourier, Transformation
Calibration	X/Y/Z-Calibration Utility
Image Processing Tool	Spatial and Fourier Low-Pass Filtering,
3	Background Subtraction, Histogram
	Equalization, Zooming, Contrast,
	Slope Correction etc.
Image Viewing	Independent nanoREV <sup>TM</sup> images (*.npic)
3	viewing & processing software for both
	Windows® & Linux platforms
Tip Locator Window	Displays current position of the tip over the sample
Nano-Lithography	In-situ tip cleaning & restructuring utility by
3 1 0	applying voltage pulses to the sample
	(-10V  to  +10V)
Color Mode Selection	Customizable color modes for the image
	(both in 2D and 3D)
Base Operating System	Linux OS kernel (2.6.17)
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System Requirements	
Processor	Pentium4 ( $\geq 2.4 \text{GHz}$ ), Pentium M ( $\geq 1.70 \text{ GHz}$ ),
	AMD Athlon/Sempron 2800+ or above
Graphics	OpenGL compatible Graphics Card, Minimum
	Resolution 1024 $\times$ 768, RAM (> 1 GB)
Computer Interface	Parallel port
Operating system	Runs from Kewti Linux Live CD/USB
	(Can also be installed onto the hard disk)
Other Features	
Spectroscopy modes	Current-Voltage, Current-Distance
Sample approach	Piezo-tube Walker, Illuminated junction view
Sample size	Sample disc dia. 10mm
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